

Notice of References Cited	Application/Control No. 10/735,480	Applicant(s)/Patent Under Reexamination PINEL ET AL.	
	Examiner Granvill D Lee, Jr	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,732,428	05-2004	Kwong, Herman	29/832
	B	US-6,143,117	11-2000	Kelly et al.	156/233
	C	US-6,759,257	07-2004	McCormack et al.	438/15
	D	US-2003/0148550	08-2003	Volant et al.	438/52
	E	US-2003/0226901	12-2003	Kim et al.	235/492
	F	US-5,317,292	05-1994	Leeb, Karl-Erik	333/238
	G	US-6,790,760	09-2004	Cohn et al.	438/613
	H	US-2002/0033342	03-2002	Uzoh et al.	205/118
	I	US-6,274,391	08-2001	Wachtler et al.	438/6
	J	US-6,016,011	01-2000	Cao et al.	257/773
	K	US-6,769,945	08-2004	Chang et al.	445/24
	L	US-5,389,569	02-1995	Cambou et al.	438/422
	M	US-5,895,967	04-1999	Stearns et al.	257/691

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2003-051566	07-2001	JPO	---	H01L 23/12
	O	2001-053548	02-2001	JPO	Yuichi	H03B 5/32
	P	10-214897	08-1998	JPO	--	H01L 21/768
	Q	2003-110244	09-2001	JPO	--	H05K 3/46
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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